- Low Supply Voltage Range 1.8 V to 3.6 V
- Ultralow-Power Consumption
  - Active Mode: 160 μA at 1 MHz, 2.2 V
  - Standby Mode: 0.7 μA
  - Off Mode (RAM Retention): 0.1 μA
- Wake-Up From Standby Mode in less than 6 μs
- 16-Bit RISC Architecture, 125 ns Instruction Cycle Time
- Basic Clock Module Configurations:
  - Various Internal Resistors
  - Single External Resistor
  - 32-kHz Crystal
  - High-Frequency Crystal
  - Resonator
  - External Clock Source
- 16-Bit Timer\_A With Three Capture/Compare Registers
- On-Chip Comparator for Analog Signal Compare Function or Slope A/D Conversion

- Serial Onboard Programming, No External Programming Voltage Needed Programmable Code Protection by Security Fuse
- Family Members Include:

MSP430C1101: 1KB ROM, 128B RAM MSP430C1111: 2KB ROM, 128B RAM MSP430C1121: 4KB ROM, 256B RAM

MSP430F1101A: 1KB + 128B Flash Memory

**128B RAM** 

MSP430F1111A: 2KB + 256B Flash Memory

**128B RAM** 

MSP430F1121A: 4KB + 256B Flash Memory

**256B RAM** 

- Available in a 20-Pin Plastic Small-Outline Wide Body (SOWB) Package, 20-Pin Plastic Small-Outline Thin Package, 20-Pin TVSOP (F11x1A only) and 24-Pin QFN
- For Complete Module Descriptions, Refer to the MSP430x1xx Family User's Guide, Literature Number SLAU049

# description

The Texas Instruments MSP430 family of ultralow power microcontrollers consist of several devices featuring different sets of peripherals targeted for various applications. The architecture, combined with five low power modes is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that attribute to maximum code efficiency. The digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 6µs.

The MSP430x11x1(A) series is an ultralow-power mixed signal microcontroller with a built-in 16-bit timer, versatile analog comparator and fourteen I/O pins.

Typical applications include sensor systems that capture analog signals, convert them to digital values, and then process the data for display or for transmission to a host system. Stand alone RF sensor front end is another area of application. The I/O port inputs provide single slope A/D conversion capability on resistive sensors.

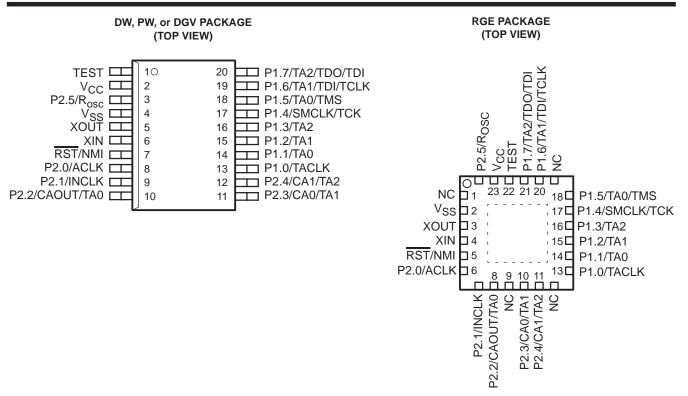
#### **AVAILABLE OPTIONS**

	PACKAGED DEVICES						
TA	PLASTIC 20-PIN SOWB (DW)	PLASTIC 20-PIN TSSOP (PW)	PLASTIC 20-PIN TVSOP (DGV)	PLASTIC 24-PIN QFN (RGE)			
-40°C to 85°C	MSP430C1101IDW MSP430C1111IDW MSP430C1121IDW MSP430F1101AIDW MSP430F1111AIDW MSP430F1121AIDW	MSP430C1101IPW MSP430C1111IPW MSP430C1121IPW MSP430F1101AIPW MSP430F1111AIPW MSP430F1121AIPW	MSP430F1101AIDGV MSP430F1111AIDGV MSP430F1121AIDGV	MSP430C1101IRGE MSP430C1111IRGE MSP430C1121IRGE MSP430F1101AIRGE MSP430F1111AIRGE MSP430F1121AIRGE			



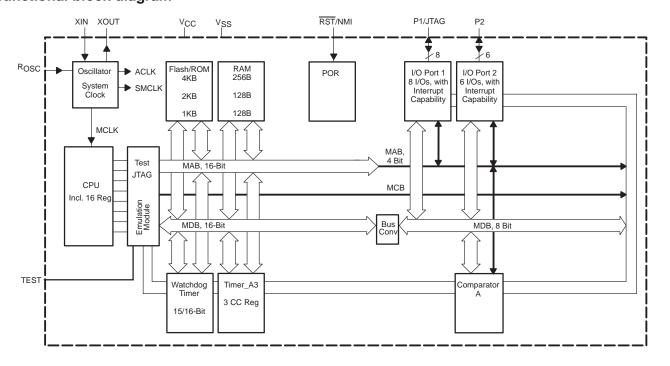
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





Note: NC pins not internally connected Power Pad connection to V<sub>SS</sub> recommended

# functional block diagram





# **Terminal Functions**

	TERMINAL			
NAME	DW, PW, or DGV	RGE	1/0	DESCRIPTION
NAME	NO.	NO.	1/0	
P1.0/TACLK	13	13	I/O	General-purpose digital I/O pin/Timer_A, clock signal TACLK input
P1.1/TA0	14	14	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0A input, compare: Out0 output/BSL transmit
P1.2/TA1	15	15	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1A input, compare: Out1 output
P1.3/TA2	16	16	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI2A input, compare: Out2 output
P1.4/SMCLK/TCK	17	17	I/O	General-purpose digital I/O pin/SMCLK signal output/test clock, input terminal for device programming and test
P1.5/TA0/TMS	18	18	I/O	General-purpose digital I/O pin/Timer_A, compare: Out0 output/test mode select, input terminal for device programming and test
P1.6/TA1/TDI/TCLK	19	20	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output/test data input or test clock input
P1.7/TA2/TDO/TDI <sup>†</sup>	20	21	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/test data output terminal or data input during programming
P2.0/ACLK	8	6	I/O	General-purpose digital I/O pin/ACLK output
P2.1/INCLK	9	7	I/O	General-purpose digital I/O pin/Timer_A, clock signal at INCLK
P2.2/CAOUT/TA0	10	8	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0B input/comparator_A, output/BSL receive
P2.3/CA0/TA1	11	10	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output/comparator_A, input
P2.4/CA1/TA2	12	11	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/comparator_A, input
P2.5/R <sub>OSC</sub>	3	24	I/O	General-purpose digital I/O pin/input for external resistor that defines the DCO nominal frequency
RST/NMI	7	5	I	Reset or nonmaskable interrupt input
TEST	1	22	I	Selects test mode for JTAG pins on Port1. The device protection fuse is connected to TEST.
Vcc	2	23		Supply voltage
V <sub>SS</sub>	4	2		Ground reference
XIN	6	4	I	Input terminal of crystal oscillator
XOUT	5	3	0	Output terminal of crystal oscillator
QFN Pad	NA	Package Pad	NA	QFN package pad connection to VSS recommended.

<sup>†</sup>TDO or TDI is selected via JTAG instruction.

# short-form description

### **CPU**

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

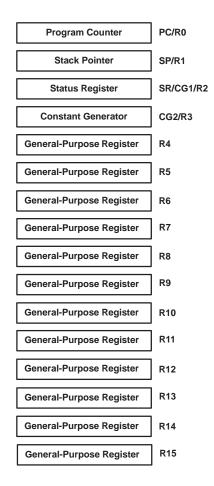
The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

#### instruction set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 1 shows examples of the three types of instruction formats; the address modes are listed in Table 2.



**Table 1. Instruction Word Formats** 

Dual operands, source-destination	e.g. ADD R4,R5	R4 + R5> R5
Single operands, destination only	e.g. CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	e.g. JNE	Jump-on-equal bit = 0

**Table 2. Address Mode Descriptions** 

ADDRESS MODE	S	D	SYNTAX	EXAMPLE	OPERATION
Register	•	•	MOV Rs,Rd	MOV R10,R11	R10> R11
Indexed	•	•	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)> M(6+R6)
Symbolic (PC relative)	•	•	MOV EDE,TONI		M(EDE)> M(TONI)
Absolute	•	•	MOV &MEM,&TCDAT		M(MEM)> M(TCDAT)
Indirect	•		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10)> M(Tab+R6)
Indirect autoincrement	•		MOV @Rn+,Rm	MOV @R10+,R11	M(R10)> R11 R10 + 2> R10
Immediate	•		MOV #X,TONI	MOV #45,TONI	#45> M(TONI)

NOTE: S = source D = destination



## operating modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode AM;
  - All clocks are active
- Low-power mode 0 (LPM0);
  - CPU is disabled ACLK and SMCLK remain active. MCLK is disabled
- Low-power mode 1 (LPM1);
  - CPU is disabled
     ACLK and SMCLK remain active. MCLK is disabled
     DCO's dc-generator is disabled if DCO not used in active mode
- Low-power mode 2 (LPM2);
  - CPU is disabled MCLK and SMCLK are disabled DCO's dc-generator remains enabled ACLK remains active
- Low-power mode 3 (LPM3);
  - CPU is disabled
     MCLK and SMCLK are disabled
     DCO's dc-generator is disabled
     ACLK remains active
- Low-power mode 4 (LPM4);
  - CPU is disabled
    ACLK is disabled
    MCLK and SMCLK are disabled
    DCO's dc-generator is disabled
    Crystal oscillator is stopped



# MSP430C11x1, MSP430F11x1A MIXED SIGNAL MICROCONTROLLER

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# interrupt vector addresses

The interrupt vectors and the power-up starting address are located in the address range of 0FFFFh–0FFE0h. The vector contains the 16-bit address of the appropriate interrupt handler instruction sequence.

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-up External reset Watchdog Flash Memory	WDTIFG KEYV (see Note 1)	Reset	0FFFEh	15, highest
NMI Oscillator fault Flash memory access violation	NMIIFG OFIFG ACCVIFG (see Notes 1 & 4)	(non)-maskable, (non)-maskable, (non)-maskable	0FFFCh	14
			0FFFAh	13
			0FFF8h	12
Comparator_A	CAIFG	maskable	0FFF6h	11
Watchdog Timer	WDTIFG	maskable	0FFF4h	10
Timer_A3	TACCR0 CCIFG (see Note 2)	maskable	0FFF2h	9
Timer_A3	TACCR1 CCIFG. TACCR2 CCIFG TAIFG (see Notes 1 & 2)	maskable	0FFF0h	8
			0FFEEh	7
			0FFECh	6
			0FFEAh	5
			0FFE8h	4
I/O Port P2 (eight flags; see Note 3)	P2IFG.0 to P2IFG.7 (see Notes 1 & 2)	maskable	0FFE6h	3
I/O Port P1 (eight flags)	P1IFG.0 to P1IFG.7 (see Notes 1 & 2)	maskable	0FFE4h	2
			0FFE2h	1
			0FFE0h	0, lowest

NOTES: 1. Multiple source flags

- 2. Interrupt flags are located in the module
- 3. There are eight Port P2 interrupt flags, but only six Port P2 I/O pins (P2.0-5) implemented on the 'C11x1 and 'F11x1A devices.
- 4. (non)-maskable: the individual interrupt-enable bit can disable an interrupt event, but the general interrupt enable cannot. Nonmaskable: neither the individual nor the general interrupt-enable bit will disable an interrupt event.



# special function registers

Most interrupt and module enable bits are collected into the lowest address space. Special function register bits not allocated to a functional purpose are not physically present in the device. Simple software access is provided with this arrangement.

# interrupt enable 1 and 2

Address	7	6	5	4	3	2	1	0
0h			ACCVIE	NMIIE			OFIE	WDTIE
			rw-0	rw-0			rw-0	rw-0
WDTIE:		Watchdog Timer interrupt enable. Inactive if watchdog mode is selected. Active if Watchdog Timer						
OFIE:		gured in inte or fault enab	rval timer m ble	ode.				
NMIIE:			rrupt enable					
ACCVIE:	Flash a	ccess violati	on interrupt	enable				
Address ,	7	6	5	4	3	2	1	0
01h								
interrupt flag i	nterrupt flag register 1 and 2							
Address	7	6	5	4	3	2	1	0
02h				NMIIFG			OFIFG	WDTIFG
				rw-0			rw-1	rw-(0)
WDTIFG:				w (in watchd				
OFIFG:		t on oscillate		set conditior	i al KSI/INIV	ii piii iii rese	et mode.	
NMIIFG:		RST/NMI-pi						
Address	7	6	5	4	3	2	1	0
03h						_		
ا								
Legend	rw:	Bit can be	e read and writt	en.				
· ·	rw-0,1:			en. It is Reset of	•			
	rw-(0,1):		e read and writt s not present in	en. It is Reset of device	or Set by POR.			
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# MSP430C11x1, MSP430F11x1A MIXED SIGNAL MICROCONTROLLER

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# memory organization

		MSP430C1101	MSP430C1111	MSP430C1121
Memory Main: interrupt vector Main: code memory	Size ROM ROM	1KB ROM 0FFFFh-0FFE0h 0FFFFh-0FC00h	2KB ROM 0FFFFh–0FFE0h 0FFFFh–0F800h	4KB ROM 0FFFFh–0FFE0h 0FFFFh–0F000h
Information memory	Size Flash	Not applicable	Not applicable	Not applicable
Boot memory	Size ROM	Not applicable	Not applicable	Not applicable
RAM	Size	128 Byte 027Fh – 0200h	128 Byte 027Fh – 0200h	256 Byte 02FFh – 0200h
Peripherals	16-bit 8-bit 8-bit SFR	01FFh – 0100h 0FFh – 010h 0Fh – 00h	01FFh – 0100h 0FFh – 010h 0Fh – 00h	01FFh – 0100h 0FFh – 010h 0Fh – 00h

		MSP430F1101A	MSP430F1111A	MSP430F1121A
Memory	Size	1KB Flash	2KB Flash	4KB Flash
Main: interrupt vector	Flash	0FFFFh-0FFE0h	0FFFFh-0FFE0h	0FFFFh-0FFE0h
Main: code memory	Flash	0FFFFh-0FC00h	0FFFFh-0F800h	0FFFFh-0F000h
Information memory	Size	128 Byte	256 Byte	256 Byte
	Flash	010FFh – 01080h	010FFh – 01000h	010FFh – 01000h
Boot memory	Size	1KB	1KB	1KB
	ROM	0FFFh – 0C00h	0FFFh – 0C00h	0FFFh – 0C00h
RAM	Size	128 Byte 027Fh – 0200h	128 Byte 027Fh – 0200h	256 Byte 02FFh – 0200h
Peripherals	16-bit	01FFh – 0100h	01FFh – 0100h	01FFh – 0100h
	8-bit	0FFh – 010h	0FFh – 010h	0FFh – 010h
	8-bit SFR	0Fh – 00h	0Fh – 00h	0Fh – 00h

# bootstrap loader (BSL)

The MSP430 bootstrap loader (BSL) enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by user-defined password. For complete description of the features of the BSL and its implementation, see the Application report *Features of the MSP430 Bootstrap Loader*, Literature Number SLAA089.

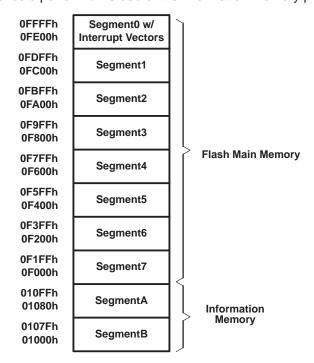
BSL Function	DW, PW & DGV Package Pins	RGE Package Pins
Data Transmit	14 - P1.1	14 - P1.1
Data Receive	10 - P2.2	8 - P2.2



## flash memory

The flash memory can be programmed via the JTAG port, the bootstrap loader, or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and two segments of information memory (A and B) of 128 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A and B can be erased individually, or as a group with segments 0-n.
   Segments A and B are also called *information memory*.
- New devices may have some bytes programmed in the information memory (needed for test during manufacturing). The user should perform an erase of the information memory prior to the first use.



NOTE: All segments not implemented on all devices.

# MSP430C11x1, MSP430F11x1A MIXED SIGNAL MICROCONTROLLER

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# peripherals

Peripherals are connected to the CPU through data, address, and control busses and can be handled using all instructions. For complete module descriptions, refer to the MSP430x1xx Family User's Guide, literature number SLAU049.

# oscillator and system clock

The clock system is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal digitally-controlled oscillator (DCO) and a high frequency crystal oscillator. The basic clock module is designed to meet the requirements of both low system cost and low-power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 6  $\mu$ s. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32768-Hz watch crystal or a high frequency crystal.
- Main clock (MCLK), the system clock used by the CPU.
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules.

# digital I/O

There are two 8-bit I/O ports implemented—ports P1 and P2 (only six P2 I/O signals are available on external pins):

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Edge-selectable interrupt input capability for all the eight bits of port P1 and six bits of port P2.
- Read/write access to port-control registers is supported by all instructions.

#### NOTE

Six bits of port P2, P2.0 to P2.5, are available on external pins – but all control and data bits for port P2 are implemented.

## watchdog timer

The primary function of the watchdog timer (WDT) module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.

# comparator\_A

The primary function of the comparator\_A module is to support precision slope analog-to-digital conversions, battery-voltage supervision, and monitoring of external analog signals.



# timer\_A3

Timer\_A3 is a 16-bit timer/counter with three capture/compare registers. Timer\_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer\_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

Timer_A3 Signal Connections							
Input Pin Number		Device Input Signal	Module Input Name	Module Block	Module Output Signal	Output Pin Number	
DW, PW, DGV	RGE					DW, PW DGV	RGE
13 - P1.0	13 - P1.0	TACLK	TACLK				
		ACLK	ACLK	] _			
		SMCLK	SMCLK	Timer	NA		
9 - P2.1	7 - P2.1	INCLK	INCLK				
14 - P1.1	14 - P1.1	TA0	CCI0A	CCR0		14 - P1.1	14 - P1.1
10 - P2.2	8 - P2.2	TA0	CCI0B		T4.0	18 - P1.5	18 - P1.5
		V <sub>SS</sub>	GND		TA0		
		Vcc	Vcc	]			
15 - P1.2	15 - P1.2	TA1	CCI1A			11 - P2.3	10 - P2.3
		CAOUT (internal)	CCI1B	0004		15 - P1.2	15 - P1.2
		VSS	GND	CCR1	TA1	19 - P1.6	20 - P1.6
		Vcc	Vcc	]			
16 - P1.3	16 - P1.3	TA2	CCI2A			12 - P2.4	11 - P2.4
		ACLK (internal)	CCI2B	CCR2		16 - P1.3	16 - P1.3
		V <sub>SS</sub>	GND		TA2	20 - P1.7	21 - P1.7
		Vcc	Vcc	]			

# peripheral file map

PER	IPHERALS WITH WORD ACCES	S	
Timer_A	Reserved Reserved Reserved Reserved Capture/compare register Capture/compare register Capture/compare register Timer_A register Reserved Reserved Reserved Reserved Capture/compare control Capture/compare control Timer_A control Timer_A interrupt vector	TACCR2 TACCR1 TACCR0 TAR  TACCTL2 TACCTL1 TACCTL0 TACTL TAIV	017Eh 017Ch 017Ah 017Ah 0178h 0176h 0172h 0170h 016Eh 016Ch 016Ah 0168h 0166h 0164h 0162h 0160h 012Eh
Flash Memory	Flash control 3 Flash control 2 Flash control 1	FCTL3 FCTL2 FCTL1	012Ch 012Ah 0128h
Watchdog	Watchdog/timer control	WDTCTL	0120h
PER	IPHERALS WITH BYTE ACCESS	S	
Comparator_A	Comparator_A port disable Comparator_A control 2 Comparator_A control 1	CAPD CACTL2 CACTL1	05Bh 05Ah 059h
Basic Clock	Basic clock system control 2 Basic clock system control 1 DCO clock frequency control	BCSCTL2 BCSCTL1 DCOCTL	058h 057h 056h
Port P2	Port P2 selection Port P2 interrupt enable Port P2 interrupt edge select Port P2 interrupt flag Port P2 direction Port P2 output Port P2 input	P2SEL P2IE P2IES P2IFG P2DIR P2OUT P2IN	02Eh 02Dh 02Ch 02Bh 02Ah 029h 028h
Port P1	Port P1 selection Port P1 interrupt enable Port P1 interrupt edge select Port P1 interrupt flag Port P1 direction Port P1 output Port P1 input	P1SEL P1IE P1IES P1IFG P1DIR P1OUT P1IN	026h 025h 024h 023h 022h 021h 020h
Special Function	SFR interrupt flag 2 SFR interrupt flag 1 SFR interrupt enable 2 SFR interrupt enable 1	IFG2 IFG1 IE2 IE1	003h 002h 001h 000h



# absolute maximum ratings†

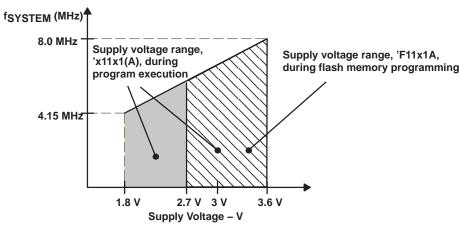
Voltage applied at V <sub>CC</sub> to V <sub>SS</sub>	
Voltage applied to any pin (see Note)	0.3 V to V <sub>CC</sub> +0.3 V
Diode current at any device terminal	±2 mA
Storage temperature, T <sub>sta</sub> (unprogrammed device)	–55°C to 150°C
Storage temperature, T <sub>sta</sub> (programmed device)	–40°C to 85°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# recommended operating conditions

			MIN	NOM	MAX	UNITS
O	a supervision V (one Nate 4)	MSP430C11x1	1.8		3.6	
Supply voltage during program	n execution, V <sub>CC</sub> (see Note 1)	MSP430F11x1A	1.8		3.6	V
Supply voltage during program	n/erase flash memory, V <sub>CC</sub>	MSP430F11x1A	2.7		3.6	V
Supply voltage, V <sub>SS</sub>	Itage, V <sub>SS</sub>		V			
Operating free-air temperature range, T <sub>A</sub>		MSP430x11x1(A)	-40		85	°C
	LF mode selected, XTS=0	Watch crystal		32768		Hz
LFXT1 crystal frequency, f(LFXT1) (see Note 1 & 2)	V=	Ceramic resonator	450		8000	
(LFX11) (See Note 1 & 2)	XT1 mode selected, XTS=1	Crystal	1000		8000	kHz
Processor frequency f <sub>(system)</sub> (MCLK signal)		V <sub>CC</sub> = 1.8 V, MSP430x11x1(A)	dc		4.15	MUL
		V <sub>CC</sub> = 3.6 V, MSP430x11x1(A)	dc		8	MHz

- NOTES: 1. In LF mode, the LFXT1 oscillator requires a watch crystal. A 5.1MΩ resistor from XOUT to V<sub>SS</sub> is recommended when V<sub>CC</sub> < 2.5 V. In XT1 mode, the LFXT1 and XT2 oscillators accept a ceramic resonator or crystal up to 4.15MHz at V<sub>CC</sub> ≥ 2.2 V. In XT1 mode, the LFXT1 and XT2 oscillators accept a ceramic resonator or crystal up to 8MHz at V<sub>CC</sub> ≥ 2.8 V.
  - 2. In LF mode, the LFXT1 oscillator requires a watch crystal. In XT1 mode, LFXT1 accepts a ceramic resonator or a crystal.



NOTE: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum  $V_{CC}$  of 2.7 V.

Figure 1. Frequency vs Supply Voltage, MSP430x11x1(A)



NOTE: All voltages referenced to VSS. The JTAG fuse-blow voltage, VFB, is allowed to exceed the absolute maximum rating. The voltage is applied to the TEST pin when blowing the JTAG fuse.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

supply current (into V<sub>CC</sub>) excluding external current

	PARAMETER			TEST CONDITIONS		MIN	TYP	MAX	UNIT
			$T_A = -40^{\circ}C$ to		V <sub>CC</sub> = 2.2 V		160	200	
		C11x1	f(MCLK) = f(S) f(ACLK) = 32	MCLK) = 1 MHz, 768 Hz	VCC = 3 V		240	300	
			$T_A = -40^{\circ}C$ to		V <sub>CC</sub> = 2.2 V		1.3	2	
				MCLK) = f(ACLK) = 4096 Hz	VCC = 3 V		2.5	3.2	
I <sub>(AM)</sub>	Active mode	ctive mode	$T_A = -40$ °C to + 85°C, $f_{MCLK} = f_{(SMCLK)} = 1$ MHz,		V <sub>CC</sub> = 2.2 V		200	250	μΑ
		F11x1A	f(ACLK) = 32, Program exec	768 Hz,	V <sub>CC</sub> = 3 V		300	350	
			$T_A = -40^{\circ}C$ to		V <sub>CC</sub> = 2.2 V		3	5	
			Program exect f(MCLK) = f(S	utes in flash MCLK) = f(ACLK) = 4096 Hz	VCC = 3 V		11	18	
		C11x1	$T_A = -40^{\circ}C$ to	+ 85°C,	V <sub>CC</sub> = 2.2 V		30	40	
	Low-power mode, (LPM0)		f(MCLK) = 0, 1 f(ACLK) = 32,	(SMCLK) = 1 MHz, 768 Hz	VCC = 3 V		51	60	
I(CPUOff)			$T_A = -40^{\circ}C$ to	+ 85°C,	V <sub>CC</sub> = 2.2 V		32	45	μΑ
		F11x1A	f(MCLK) = 0, f f(ACLK) = 32, f	(SMCLK) = 1 MHz, 768 Hz	V <sub>CC</sub> = 3 V		55	70	
	Low-power mode,	•	$T_A = -40^{\circ}C$ to	$V_{C} = -40^{\circ}\text{C to} + 85^{\circ}\text{C},$ $V_{C} = -40^{\circ}\text{C}$			11	14	_
I(LPM2)	(LPM2)		f(MCLK) = f(S) f(ACLK) = 32	MCLK) = 0 MHz, 768 Hz, SCG0 = 0	V <sub>CC</sub> = 3 V		17	22	μΑ
	$T_{A} = -40^{\circ}\text{C to} + 85^{\circ}\text{C},$		V <sub>CC</sub> = 2.2 V		1.2	1.7			
			f(MCLK) = f(S) f(ACLK) = 32	MCLK) = 0 MHz, 768 Hz, SCG0 = 1	V <sub>CC</sub> = 3 V		2	2.7	
			$T_A = -40^{\circ}C$				0.8	1.2	
I <sub>(LPM3)</sub>	Low-power mode, (LPM3)		T <sub>A</sub> = 25°C	f(MCLK) = 0 MHz,	V <sub>CC</sub> = 2.2 V		0.7	1	μΑ
(LFIVIS)	(2. 1110)	F11x1A	T <sub>A</sub> = 85°C	f(SMCLK) = 0 MHz,			1.6	2.3	p
		FTIXTA	T <sub>A</sub> = −40°C	f(ACLK) = 32,768 Hz,			1.8	2.2	
			T <sub>A</sub> = 25°C	SCG0 = 1	V <sub>CC</sub> = 3 V		1.6	1.9	
	T <sub>A</sub> = 85°C				2.3	3.4			
	T <sub>A</sub> =	T <sub>A</sub> = −40°C				0.1	0.5		
		C11x1	T <sub>A</sub> = 25°C		V <sub>CC</sub> = 2.2 V/3 V		0.1	0.5	
1	Low-power mode,		T <sub>A</sub> = 85°C	f(MCLK) = 0 MHz			0.4	0.8	
I(LPM4)	(LPM4)		T <sub>A</sub> = −40°C	f(SMCLK) = 0 MHz, f(ACLK) = 0 Hz, SCG0 = 1			0.1	0.5	- μΑ
			T <sub>A</sub> = 25°C	- (ACLK) - 0112, 3000 = 1	V <sub>CC</sub> = 2.2 V/3 V		0.1	0.5	
			T <sub>A</sub> = 85°C				0.8	1.9	

NOTE: All inputs are tied to 0 V or V<sub>CC</sub>. Outputs do not source or sink any current.

current consumption of active mode versus system frequency, C version, F version

 $I_{AM} = I_{AM[1 \text{ MHz}]} \times f_{system} [MHz]$ 

current consumption of active mode versus supply voltage, C version

 $I_{AM} = I_{AM[3\ V]} + 105\ \mu\text{A/V} \times (V_{CC} - 3\ V)$ 

current consumption of active mode versus supply voltage, F version

 $I_{AM} = I_{AM[3\ V]} + 120\ \mu A/V \times (V_{CC} - 3\ V)$ 



## Schmitt-trigger inputs – Ports P1 and P2; (P1.0 to P1.7, P2.0 to P2.5)

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
.,	Decitive acing input threehold values	V <sub>CC</sub> = 2.2 V	1.1	1.5	V
V <sub>IT+</sub>	Positive-going input threshold voltage	V <sub>CC</sub> = 3 V	1.5	1.9	\ \ \
\/-	V <sub>IT</sub> _ Negative-going input threshold voltage	V <sub>CC</sub> = 2.2 V	0.4	0.9	\/
VIT-		V <sub>CC</sub> = 3 V	0.9	1.3	\ \ \
V.	Input voltage bystoresis (// // )	V <sub>CC</sub> = 2.2 V	0.3	1.1	V
V <sub>hys</sub>	Input voltage hysteresis (V <sub>IT+</sub> – V <sub>IT</sub> _)	V <sub>CC</sub> = 3 V	0.5	1	V

# standard inputs - RST/NMI, JTAG: TCK, TMS, TDI/TCLK

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
VIL	Low-level input voltage	V <sub>CC</sub> = 2.2 V / 3 V	VSS	V <sub>SS</sub> +0.6	V
VIH	High-level input voltage	vCC = 2.2 v / 3 v	0.8×V <sub>CC</sub>	Vcc	V

### inputs Px.x, TAx

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
			2.2 V/3 V	1.5			cycle
t(int)	External interrupt timing	Port P1, P2: P1.x to P2.x, External trigger signal for the interrupt flag, (see Note 1)	2.2 V	62			ns
, ,		To the interrupt mag, (eee rester)	3 V	50			
_	t <sub>(cap)</sub> Timer_A, capture timing TA0, TA1, TA2	2.2 V	62				
t(cap)		1A0, 1A1, 1A2	3 V	50			ns
4	Timer_A clock frequency	TACLK INCLKA A	2.2 V			8	MI I-
f(TAext)	externally applied to pin	TACLK, INCLK $t(H) = t(L)$	3 V			10	MHz
,	Town A death for more		2.2 V			8	N 41 1-
f(TAint)	Timer_A clock frequency	SMCLK or ACLK signal selected	3 V			10	MHz

NOTES: 1. The external signal sets the interrupt flag every time the minimum  $t_{(int)}$  cycle and time parameters are met. It may be set even with trigger signals shorter than  $t_{(int)}$ . Both the cycle and timing specifications must be met to ensure the flag is set.  $t_{(int)}$  is measured in MCLK cycles.

## leakage current

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Ī	I Cole Communication of the Communication	Port P1: P1.x, $0 \le x \le 7$ (see Notes 1, 2)	$V_{CC} = 2.2 \text{ V/3 V},$			±50	- 4
	I <sub>Ikg(Px.x)</sub> High-impedance leakage current	Port P2: P2.x, $0 \le x \le 5$ (see Notes 1, 2)	$V_{CC} = 2.2 \text{ V/3 V},$	·		±50	nA

NOTES: 1. The leakage current is measured with  $V_{SS}$  or  $V_{CC}$  applied to the corresponding pin(s), unless otherwise noted.

2. The leakage of the digital port pins is measured individually. The port pin must be selected for input and there must be no optional pullup or pulldown resistor.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

outputs - Ports P1 and P2; (P1.0 to P1.7, P2.0 to P2.5)

	PARAMETER	TEST	CONDITIONS		MIN	TYP MAX	UNIT
		$I_{(OHmax)} = -1.5 \text{ mA}$	v 00v	See Note 1	V <sub>CC</sub> -0.25	Vcc	
l.,	High-level output voltage Port 1 and Port 2 (C11x1)	$I_{(OHmax)} = -6 \text{ mA}$	$V_{CC} = 2.2 \text{ V}$	See Note 2	VCC-0.6	Vcc	V
VOH	Port 1 (F11x1A)	$I_{(OHmax)} = -1.5 \text{ mA}$	$V_{CC} = 3 V$	See Note 1	V <sub>CC</sub> -0.25	Vcc	V
	,	$I_{(OHmax)} = -6 \text{ mA}$		See Note 2	VCC-0.6	Vcc	
		$I_{(OHmax)} = -1 \text{ mA}$	Vcc = 22 V	See Note 3	V <sub>CC</sub> -0.25	Vcc	
V	High-level output voltage	$I_{(OHmax)} = -3.4 \text{ mA}$		See Note 3	V <sub>CC</sub> -0.6	V <sub>CC</sub>	\/
VOH	Port 2 (F11x1A)	$I_{(OHmax)} = -1 \text{ mA}$	a.v	See Note 3	V <sub>CC</sub> -0.25	Vcc	V
		$I_{(OHmax)} = -3.4 \text{ mA}$	VCC = 3 V	See Note 3	V <sub>CC</sub> -0.6	VCC	
		$I_{(OLmax)} = 1.5 \text{ mA}$	V 00V	See Note 1	VSS	V <sub>SS</sub> +0.25	
	Low-level output voltage	I <sub>(OLmax)</sub> = 6 mA	$V_{CC} = 2.2 \text{ V}$	See Note 2	VSS	V <sub>SS</sub> +0.6	V
VOL	Port 1 and Port 2 (C11x1, F11x1A)	$I_{(OLmax)} = 1.5 \text{ mA}$	V 2.V	See Note 1	VSS	V <sub>SS</sub> +0.25	V
	,	I <sub>(OLmax)</sub> = 6 mA	VCC = 3 V	See Note 2	VSS	V <sub>SS</sub> +0.6	

NOTES: 1. The maximum total current, I<sub>OHmax</sub> and I<sub>OLmax</sub>, for all outputs combined, should not exceed ±12 mA to hold the maximum voltage drop specified.

- 2. The maximum total current, I<sub>OHmax</sub> and I<sub>OLmax</sub>, for all outputs combined, should not exceed ±48 mA to hold the maximum voltage drop specified.
- 3. One output loaded at a time.

# output frequency

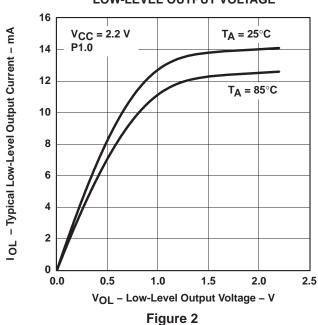
F	PARAMETER	TEST	CONDITIONS	VCC	MIN	TYP	MAX	UNIT	
f <sub>P20</sub>		P2.0/ACLK, C <sub>L</sub> = 20 pF		2.2 V/3 V			fSystem		
f <sub>TAx</sub>	Output frequency	TA0, TA1, TA2, C <sub>L</sub> = 20 p Internal clock source, SM	D, TA1, TA2, C <sub>L</sub> = 20 pF ernal clock source, SMCLK signal applied (see Note 1)				fSystem	MHz	
			fSMCLK = fLFXT1 = fXT1	2.2 V/3 V	40%		60%		
		D4 4/CMCLV	fSMCLK = fLFXT1 = fLF		22 V/3 V	35%		65%	
		P1.4/SMCLK, C <sub>L</sub> = 20 pF	fSMCLK = fLFXT1/n		50%– 15 ns	50%	50%+ 15 ns		
<sup>t</sup> Xdc	Duty cycle of O/P frequency		fSMCLK = fDCOCLK	2.2 V/3 V	50%– 15 ns	50%	50%+ 15 ns		
			f <sub>P20</sub> = f <sub>LFXT1</sub> = f <sub>XT1</sub>		40%		60%		
		P2.0/ACLK, C <sub>1</sub> = 20 pF	f <sub>P20</sub> = f <sub>LFXT1</sub> = f <sub>LF</sub>	2.2 V/3 V	30%		70%		
		fP20 = fLFXT1/n				50%			
tTAdc		TA0, TA1, TA2, $C_L = 20 p$	F, duty cycle = 50%	2.2 V/3 V		0	±50	ns	

NOTE 1: The limits of the system clock MCLK has to be met. MCLK and SMCLK can have different frequencies.

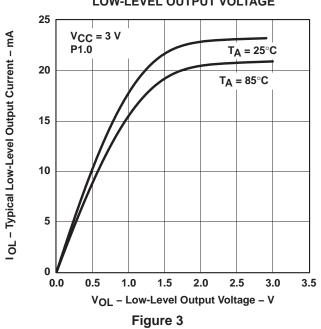


outputs - Ports P1 and P2 (continued)

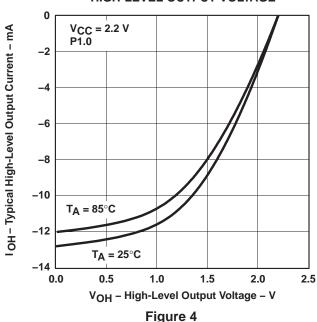
# TYPICAL LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE



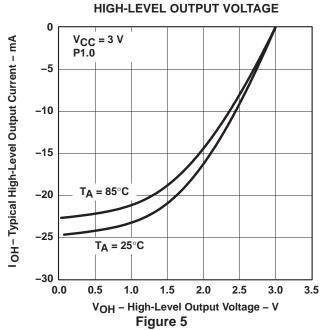
# TYPICAL LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE



# TYPICAL HIGH-LEVEL OUTPUT CURRENT vs HIGH-LEVEL OUTPUT VOLTAGE



TYPICAL HIGH-LEVEL OUTPUT CURRENT vs



NOTE: One output loaded at a time.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

## optional resistors, individually programmable with ROM code (see Note 1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
R <sub>(opt1)</sub>			2.5	5	10	kΩ
R <sub>(opt2)</sub>			3.8	7.7	15	kΩ
R <sub>(opt3)</sub>			7.6	15	31	kΩ
R <sub>(opt4)</sub>			11.5	23	46	kΩ
R <sub>(opt5)</sub>	Resistors, individually programmable with ROM code, all port pins,	V <sub>CC</sub> = 2.2 V/3 V	23	45	90	kΩ
R <sub>(opt6)</sub>	values applicable for pulldown and pullup		46	90	180	kΩ
R <sub>(opt7)</sub>			70	140	280	kΩ
R <sub>(opt8)</sub>			115	230	460	kΩ
R <sub>(opt9)</sub>			160	320	640	kΩ
R <sub>(opt10)</sub>			205	420	830	kΩ

NOTE 1: Optional resistors R<sub>Optx</sub> for pulldown or pullup are not available in standard flash memory device MSP430F11x1A.

# wake-up from lower power modes (LPMx)

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t(LPM0)		V <sub>CC</sub> = 2.2 V/3 V			100		
t(LPM2)		V <sub>CC</sub> = 2.2 V/3 V			100		ns
		f(MCLK) = 1 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	
t(LPM3)	Deleviting (see Note 4)	f(MCLK) = 2 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	μs
	Delay time (see Note 1)	f(MCLK) = 3 MHz,	$V_{CC} = 2.2 \text{ V/3 V}$			6	
		f <sub>(MCLK)</sub> = 1 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	
t(LPM4)		f(MCLK) = 2 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	μs
		f(MCLK) = 3 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	

NOTE 1: Parameter applicable only if DCOCLK is used for MCLK.

#### **RAM**

	PARAMETER	MIN	NOM	MAX	UNIT
V(RAMh)	CPU halted (see Note 1)	1.6			V

NOTE 1: This parameter defines the minimum supply voltage V<sub>CC</sub> when the data in the program memory RAM remains unchanged. No program execution should happen during this supply voltage condition.

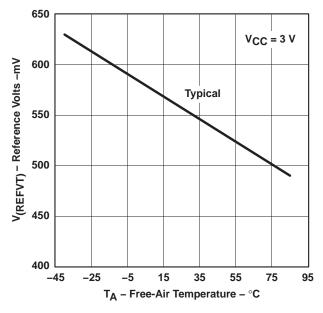


## Comparator\_A (see Note 1)

	PARAMETER	TEST CONDITIONS	3	MIN	TYP	MAX	UNIT
lon		CAON=1, CARSEL=0, CAREF=0	V <sub>CC</sub> = 2.2 V		25	40	
I(DD)		CAON=1, CARSEL=0, CAREF=0	V <sub>CC</sub> = 3 V		45	60	μΑ
		CAON=1, CARSEL=0,	V <sub>CC</sub> = 2.2 V		30	50	
<sup>I</sup> (Refladder/F	RefDiode)	CAREF=1/2/3, no load at P2.3/CA0/TA1 and P2.4/CA1/TA2	VCC = 3 V		45	71	μΑ
V <sub>(IC)</sub>	Common-mode input voltage	CAON =1	V <sub>CC</sub> = 2.2 V/3 V	0		V <sub>CC</sub> -1	V
V(Ref025)	Voltage @ 0.25 V <sub>CC</sub> node	PCA0=1, CARSEL=1, CAREF=1, No load at P2.3/CA0/TA1 and P2.4/CA1/TA2	V <sub>CC</sub> = 2.2 V/3 V	0.23	0.24	0.25	
V(Ref050)	Voltage @ 0.5V <sub>CC</sub> node	PCA0=1, CARSEL=1, CAREF=2, No load at P2.3/CA0/TA1 and P2.4/CA1/TA2	V <sub>CC</sub> = 2.2 V/3 V	0.47	0.48	0.5	
		PCA0=1, CARSEL=1, CAREF=3,	V <sub>CC</sub> = 2.2 V	390	480		
V(RefVT)	(see Figure 6 and Figure 7)	No load at P2.3/CA0/TA1 and	V <sub>CC</sub> = 3 V	400	490		mV
V <sub>(offset)</sub>	Offset voltage	See Note 2	V <sub>CC</sub> = 2.2 V/3 V	-30		30	mV
V <sub>hys</sub>	Input hysteresis	CAON=1	V <sub>CC</sub> = 2.2 V/3 V	0	0.7	1.4	mV
		T <sub>A</sub> = 25°C, Overdrive 10 mV,	V <sub>CC</sub> = 2.2 V	160	210	300	20
		Without filter: CAF=0	V <sub>CC</sub> = 3 V	90	150	240	ns
<sup>t</sup> (response L	.H)	T <sub>A</sub> = 25°C, Overdrive 10 mV,	V <sub>CC</sub> = 2.2 V	1.4	1.9	3.4	
		With filter: CAF=1	VCC = 3 V	0.9	1.5	2.6	μs
	<u> </u>	T <sub>A</sub> = 25°C, Overdrive 10 mV,	V <sub>CC</sub> = 2.2 V	130	210	300	20
		Without filter: CAF=0	V <sub>C</sub> C = 3 V	80	150	240	ns
t(response F	HL)	T <sub>A</sub> = 25°C, Overdrive 10 mV,	V <sub>CC</sub> = 2.2 V	1.4	1.9	3.4	
		With filter: CAF=1	VCC = 3 V	0.9	1.5	2.6	μs

NOTES: 1. The leakage current for the Comparator\_A terminals is identical to I<sub>lkg(Px.x)</sub> specification.

2. The input offset voltage can be cancelled by using the CAEX bit to invert the Comparator\_A inputs on successive measurements. The two successive measurements are then summed together.



650 V<sub>CC</sub> = 2.2 V V(REFVT) - Reference Volts -mV 600 **Typical** 550 500 450 400 -45 -25 15 35 55 75 95  $T_A$  – Free-Air Temperature –  $^{\circ}C$ 

Figure 6.  $V_{(RefVT)}$  vs Temperature,  $V_{CC} = 3 V$ 

Figure 7.  $V_{(RefVT)}$  vs Temperature,  $V_{CC}$  = 2.2 V

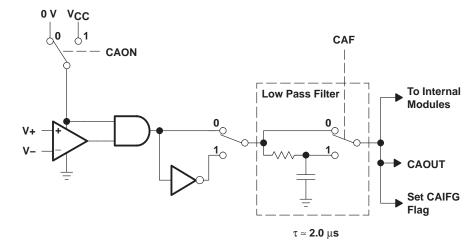


Figure 8. Block Diagram of Comparator\_A Module

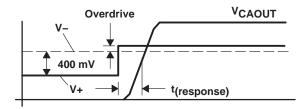


Figure 9. Overdrive Definition



## **PUC/POR**

	PARAMETER	TEST CONDIT	IONS	MIN	TYP	MAX	UNIT
t(POR_Delay)	Internal time delay to release POR				150	250	μs
	VCC threshold at which POR	$T_A = -40^{\circ}C$	]	1.4		1.8	V
V <sub>POR</sub>	release delay time begins	$T_A = 25^{\circ}C$		1.1		1.5	V
	(see Note 1)	T <sub>A</sub> = 85°C	$V_{CC} = 2.2 \text{ V/3 V}$	0.8		1.2	V
V <sub>(min)</sub>	V <sub>CC</sub> threshold required to generate a POR (see Note 2)	V <sub>CC</sub>  dV/dt  ≥ 1V/ms		0.2			V
t(reset)	RST/NMI low time for PUC/POR	Reset is accepted internally		2			μs

NOTES: 1.  $V_{CC}$  rise time  $dV/dt \ge 1V/ms$ .

2. When driving  $V_{CC}$  low in order to generate a POR condition,  $V_{CC}$  should be driven to 200mV or lower with a dV/dt equal to or less than -1V/ms. The corresponding rising  $V_{CC}$  must also meet the dV/dt requirement equal to or greater than +1V/ms.

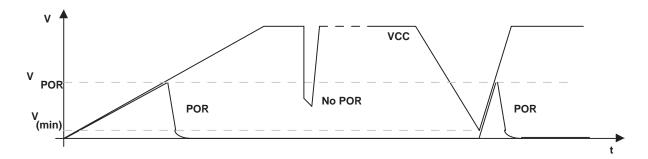


Figure 10. Power-On Reset (POR) vs Supply Voltage

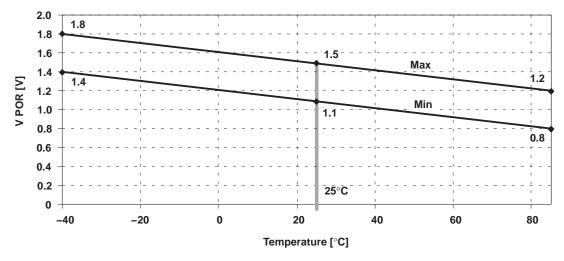


Figure 11. V<sub>POR</sub> vs Temperature

#### **DCO**

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
,	D 0 000 0 MOD 0 0000 0 T 0500	V <sub>CC</sub> = 2.2 V	0.08	0.12	0.15	
f(DCO03)	$R_{sel} = 0$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	V <sub>CC</sub> = 3 V	0.08	0.13	0.16	MHz
£	D . 4 DCO 2 MOD 0 DCOD 0 T. 25°C	V <sub>CC</sub> = 2.2 V	0.14	0.19	0.23	MHz
f(DCO13)	$R_{sel} = 1$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	V <sub>CC</sub> = 3 V	0.14	0.18	0.22	IVITZ
f(DCO23)	$R_{SO} = 2$ , DCO = 3, MOD = 0, DCOR = 0, $T_{\Delta} = 25^{\circ}$ C	V <sub>CC</sub> = 2.2 V	0.22	0.30	0.36	MHz
·(DCO23)	Ngg  = 2, Boo = 0, Mob = 0, Book = 0, 1A = 20 0	VCC = 3 V	0.22	0.28	0.34	1411 12
f(DOOSS)	$R_{Sel} = 3$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25^{\circ}$ C	V <sub>CC</sub> = 2.2 V	0.37	0.49	0.59	MHz
f(DCO33)	NSE  = 3, DOO = 3, WOD = 0, DOON = 0, 1A = 23 C	$V_{CC} = 3 V$	0.37	0.47	0.56	IVII IZ
f(DOO (0)	$R_{Sel} = 4$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25^{\circ}C$	$V_{CC} = 2.2 \text{ V}$	0.61	0.77	0.93	MHz
f(DCO43)	NSE  = 4, DCO = 3, WOD = 0, DCON = 0, 1A = 23 C	V <sub>CC</sub> = 3 V	0.61	0.75	0.9	IVII IZ
f(DOCES)	$R_{SO} = 5$ , DCO = 3, MOD = 0, DCOR = 0, $T_{\Delta} = 25^{\circ}$ C	V <sub>CC</sub> = 2.2 V	1	1.2	1.5	MHz
f(DCO53)	N <sub>Sel</sub> = 3, DCO = 3, MOD = 0, DCOR = 0, 1 <sub>A</sub> = 23 C	VCC = 3 V	1	1.3	1.5	IVII IZ
f(DOCOC)	$R_{Sel} = 6$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25^{\circ}C$	V <sub>CC</sub> = 2.2 V	1.6	1.9	2.2	MHz
f(DCO63)	$ R_{Sel}  = 0$ , $DCO = 3$ , $MOD = 0$ , $DCOR = 0$ , $ I_A  = 23$ C	V <sub>CC</sub> = 3 V	1.69	2	2.29	IVIITZ
f /= ·	$R_{Sel} = 7$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25^{\circ}C$	V <sub>CC</sub> = 2.2 V	2.4	2.9	3.4	MHz
f(DCO73)	$ R_{Sel}=7, DCO=3, MOD=0, DCOR=0,  IA=23 C$	V <sub>CC</sub> = 3 V	2.7	3.2	3.65	IVIITZ
	D 7 DOO 7 HOD 0 DOOD 0 T 0500	V <sub>CC</sub> = 2.2 V	4	4.5	4.9	N 41 1-
f(DCO77)	$R_{Sel} = 7$ , DCO = 7, MOD = 0, DCOR = 0, $T_A = 25$ °C	V <sub>CC</sub> = 3 V	4.4	4.9	5.4	MHz
f(DCO47)	R <sub>Sel</sub> = 4, DCO = 7, MOD = 0, DCOR = 0, T <sub>A</sub> = 25°C	V <sub>CC</sub> = 2.2 V/3 V	fDCO40 x1.7	fDCO40 x2.1	fDCO40 x2.5	MHz
S <sub>(Rsel)</sub>	S <sub>R</sub> = f <sub>Rsel+1</sub> /f <sub>Rsel</sub>	V <sub>CC</sub> = 2.2 V/3 V	1.35	1.65	2	
S <sub>(DCO)</sub>	S <sub>DCO</sub> = f <sub>DCO+1</sub> /f <sub>DCO</sub>	V <sub>CC</sub> = 2.2 V/3 V	1.07	1.12	1.16	ratio
	Temperature drift, R <sub>sel</sub> = 4, DCO = 3, MOD = 0	V <sub>CC</sub> = 2.2 V	-0.31	-0.36	-0.40	04.400
Dt	(see Note 1)	V <sub>CC</sub> = 3 V	-0.33	-0.38	-0.43	%/°C
DV	Drift with V <sub>CC</sub> variation, R <sub>Sel</sub> = 4, DCO = 3, MOD = 0 (see Note 1)	V <sub>CC</sub> = 2.2 V/3 V	0	5	10	%/V

NOTE 1: These parameters are not production tested.

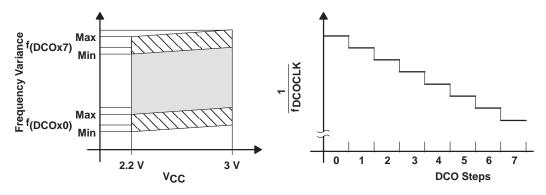


Figure 12. DCO Characteristics



#### main DCO characteristics

- Individual devices have a minimum and maximum operation frequency. The specified parameters for f<sub>(DCOx0)</sub> to f<sub>(DCOx7)</sub> are valid for all devices.
- All ranges selected by Rsel(n) overlap with Rsel(n+1): Rsel0 overlaps Rsel1, ... Rsel6 overlaps Rsel7.
- DCO control bits DCO0, DCO1, and DCO2 have a step size as defined by parameter S<sub>DCO</sub>.
- Modulation control bits MOD0 to MOD4 select how often  $f_{(DCO+1)}$  is used within the period of 32 DCOCLK cycles. The frequency  $f_{(DCO)}$  is used for the remaining cycles. The frequency is an average equal to:

$$f_{average} = \frac{32 \times f_{(DCO)} \times f_{(DCO+1)}}{MOD \times f_{(DCO)} + (32 - MOD) \times f_{(DCO+1)}}$$

# DCO when using R<sub>OSC</sub> (see Note 1)

	•				
PARAMETER	TEST CONDITIONS	VCC	MIN NOM	MAX	UNIT
for a p DCO output fraguessor	R <sub>sel</sub> = 4, DCO = 3, MOD = 0, DCOR = 1,	2.2 V	1.8±15%		MHz
f <sub>DCO</sub> , DCO output frequency	T <sub>A</sub> = 25°C	3 V	1.95±15%		MHz
D <sub>t</sub> , Temperature drift	R <sub>Sel</sub> = 4, DCO = 3, MOD = 0, DCOR = 1	2.2 V/3 V	±0.1		%/°C
D <sub>V</sub> , Drift with V <sub>CC</sub> variation	R <sub>Sel</sub> = 4, DCO = 3, MOD = 0, DCOR = 1	2.2 V/3 V	10		%/V

NOTES: 1.  $R_{OSC} = 100 k\Omega$ . Metal film resistor, type 0257. 0.6 watt with 1% tolerance and  $T_K = \pm 50 ppm/^{\circ}C$ .

### crystal oscillator, LFXT1

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
		XTS=0; LF mode selected. V <sub>CC</sub> = 2.2 V / 3 V	12		
C <sub>XIN</sub>	Input capacitance	XTS=1; XT1 mode selected. VCC = 2.2 V / 3 V (see Note 1)	2		pF
0	Output consistence	XTS=0; LF mode selected. V <sub>CC</sub> = 2.2 V / 3 V	12		
Схоит	Output capacitance	XTS=1; XT1 mode selected. VCC = 2.2 V / 3 V (see Note 1)	2		pF
$V_{IL}$	Input levels at XIN	V <sub>CC</sub> = 2.2 V/3 V (see Note 2)	V <sub>SS</sub> 0	.2×V <sub>CC</sub>	V
VIH	inpatiovoid at Aliv	100 = 2.2 1/3 1 (330 11010 2)	0.8×VCC	Vcc	•

NOTES: 1. Requires external capacitors at both terminals. Values are specified by crystal manufacturers.

2. Applies only when using an external logic-level clock source. Not applicable when using a crystal or resonator.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

### Flash Memory

	PARAMETER	TEST CONDITIONS	VCC	MIN	NOM	MAX	UNIT
VCC(PGM/ ERASE)	Program and Erase supply voltage			2.7		3.6	٧
fFTG	Flash Timing Generator frequency			257		476	kHz
IPGM	Supply current from V <sub>CC</sub> during program		2.7 V/ 3.6 V		3	5	mA
IERASE	Supply current from V <sub>CC</sub> during erase		2.7 V/ 3.6 V		3	7	mA
t <sub>CPT</sub>	Cumulative program time	see Note 1	2.7 V/ 3.6 V			4	ms
<sup>t</sup> CMErase	Cumulative mass erase time	see Note 2	2.7 V/ 3.6 V	200			ms
	Program/Erase endurance			10 <sup>4</sup>	10 <sup>5</sup>		cycles
<sup>t</sup> Retention	Data retention duration	T <sub>J</sub> = 25°C		100			years
t <sub>Word</sub>	Word or byte program time				35		
<sup>t</sup> Block, 0	Block program time for 1 <sup>St</sup> byte or word				30		
<sup>t</sup> Block, 1-63	Block program time for each additional byte or word	N-4- 2			21		4
<sup>t</sup> Block, End	Block program end-sequence wait time	see Note 3			6		tFTG
t <sub>Mass Erase</sub> Mass erase time					5297		
tSeg Erase	Segment erase time				4819		

- NOTES: 1. The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.
  - 2. The mass erase duration generated by the flash timing generator is at least 11.1ms (= 5297x1/fFTG,max = 5297x1/476kHz). To achieve the required cumulative mass erase time the Flash Controller's mass erase operation can be repeated until this time is met. (A worst case minimum of 19 cycles are required).
  - 3. These values are hardwired into the Flash Controller's state machine ( $t_{FTG} = 1/f_{FTG}$ ).

#### **JTAG Interface**

	PARAMETER		Vcc	MIN	NOM	MAX	UNIT
,	TOK:	and Material	2.2 V	0		5	MHz
TCK	TCK input frequency	see Note 1	3 V	0		10	MHz
R <sub>Internal</sub>	Internal pull-down resistance on TEST	see Note 2	2.2 V/ 3 V	25	60	90	kΩ

NOTES: 1. f<sub>TCK</sub> may be restricted to meet the timing requirements of the module selected.

2. TEST pull-down resistor implemented in all versions.

# JTAG Fuse (see Note 1)

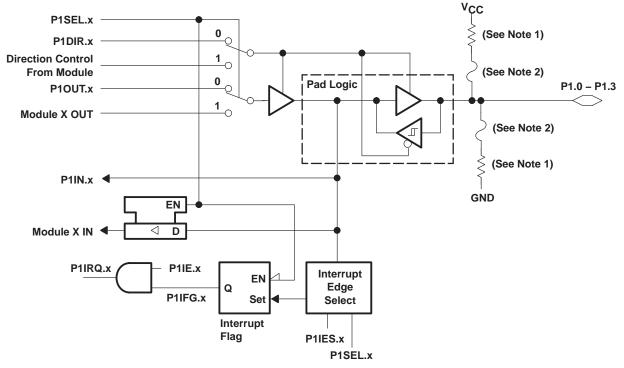
	PARAMETER	TEST CONDITIONS	vcc	MIN	NOM	MAX	UNIT
V <sub>CC(FB)</sub>	Supply voltage during fuse-blow condition	T <sub>A</sub> = 25°C		2.5			V
.,	Voltage level on TEST for fuse-blow - 'C11x1			3.5		3.9	V
V <sub>FB</sub>	Voltage level on TEST for fuse-blow - 'F11x1A			6		7	V
I <sub>FB</sub>	Supply current into TEST during fuse blow					100	mA
t <sub>FB</sub>	Time to blow fuse					1	ms

NOTES: 1. Once the fuse is blown, no further access to the MSP430 JTAG/Test and emulation features is possible. The JTAG block is switched to bypass mode.



# input/output schematic

# Port P1, P1.0 to P1.3, input/output with Schmitt-trigger



NOTE: x = Bit/identifier, 0 to 3 for port P1

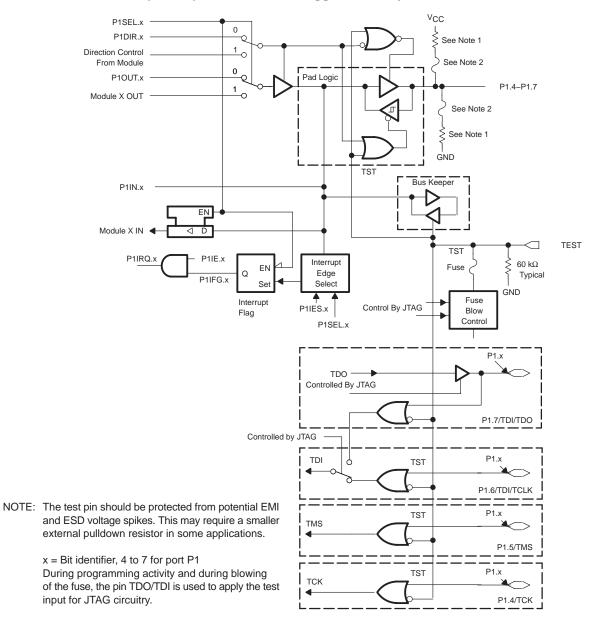
PnSel.x	PnDIR.x	Direction control from module	PnOUT.x	Module X OUT	PnIN.x	Module X IN	PnIE.x	PnIFG.x	PnIES.x
P1Sel.0	P1DIR.0	P1DIR.0	P1OUT.0	V <sub>SS</sub>	P1IN.0	TACLK <sup>†</sup>	P1IE.0	P1IFG.0	P1IES.0
P1Sel.1	P1DIR.1	P1DIR.1	P1OUT.1	Out0 signal†	P1IN.1	CCI0A†	P1IE.1	P1IFG.1	P1IES.1
P1Sel.2	P1DIR.2	P1DIR.2	P1OUT.2	Out1 signal <sup>†</sup>	P1IN.2	CCI1A <sup>†</sup>	P1IE.2	P1IFG.2	P1IES.2
P1Sel.3	P1DIR.3	P1DIR.3	P1OUT.3	Out2 signal†	P1IN.3	CCI2A†	P1IE.3	P1IFG.3	P1IES.3

<sup>†</sup> Signal from or to Timer\_A

NOTES: 1. Optional selection of pullup or pulldown resistors with ROM (masked) versions

<sup>2.</sup> Fuses for optional pullup and pulldown resistors can only be programmed at the factory (ROM versions only).

## Port P1, P1.4 to P1.7, input/output with Schmitt-trigger and in-system access features



PnSel.x	PnDIR.x	Direction control from module	PnOUT.x	Module X OUT	PnIN.x	Module X IN	PnIE.x	PnIFG.x	PnlES.x
P1Sel.4	P1DIR.4	P1DIR.4	P1OUT.4	SMCLK	P1IN.4	unused	P1IE.4	P1IFG.4	P1IES.4
P1Sel.5	P1DIR.5	P1DIR.5	P1OUT.5	Out0 signal†	P1IN.5	unused	P1IE.5	P1IFG.5	P1IES.5
P1Sel.6	P1DIR.6	P1DIR.6	P1OUT.6	Out1 signal <sup>†</sup>	P1IN.6	unused	P1IE.6	P1IFG.6	P1IES.6
P1Sel.7	P1DIR.7	P1DIR.7	P1OUT.7	Out2 signal <sup>†</sup>	P1IN.7	unused	P1IE.7	P1IFG.7	P1IES.7

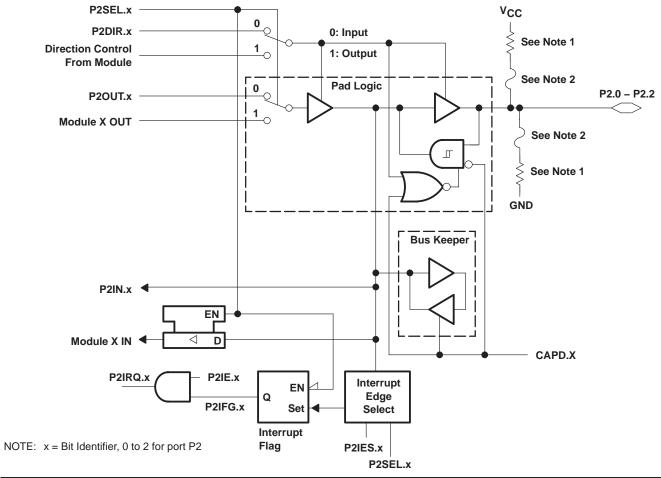
TSignal from or to Timer\_A

NOTES: 1. Optional selection of pullup or pulldown resistors with ROM (masked) versions

<sup>2.</sup> Fuses for optional pullup and pulldown resistors can only be programmed at the factory (ROM versions only).



# Port P2, P2.0 to P2.2, input/output with Schmitt-trigger



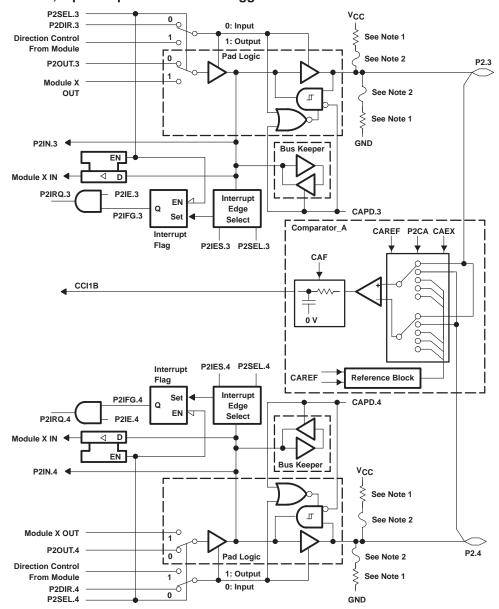
PnSel.x	PnDIR.x	Direction control from module	PnOUT.x	Module X OUT	PnIN.x	Module X IN	PnIE.x	PnIFG.x	PnIES.x
P2Sel.0	P2DIR.0	P2DIR.0	P2OUT.0	ACLK	P2IN.0	unused	P2IE.0	P2IFG.0	P1IES.0
P2Sel.1	P2DIR.1	P2DIR.1	P2OUT.1	V <sub>SS</sub>	P2IN.1	INCLK <sup>†</sup>	P2IE.1	P2IFG.1	P1IES.1
P2Sel.2	P2DIR.2	P2DIR.2	P2OUT.2	CAOUT	P2IN.2	CCI0B <sup>†</sup>	P2IE.2	P2IFG.2	P1IES.2

<sup>†</sup> Signal from or to Timer\_A

NOTES: 1. Optional selection of pullup or pulldown resistors with ROM (masked) versions

2. Fuses for optional pullup and pulldown resistors can only be programmed at the factory (ROM versions only).

## Port P2, P2.3 to P2.4, input/output with Schmitt-trigger



PnSel.x	PnDIR.x	Direction control from module	PnOUT.x	Module X OUT	PnIN.x	Module X IN	PnIE.x	PnIFG.x	PnIES.x
P2Sel.3	P2DIR.3	P2DIR.3	P2OUT.3	Out1 signal <sup>†</sup>	P2IN.3	unused	P2IE.3	P2IFG.3	P1IES.3
P2Sel.4	P2DIR.4	P2DIR.4	P2OUT.4	Out2 signal <sup>†</sup>	P2IN.4	unused	P2IE.4	P2IFG.4	P1IES.4

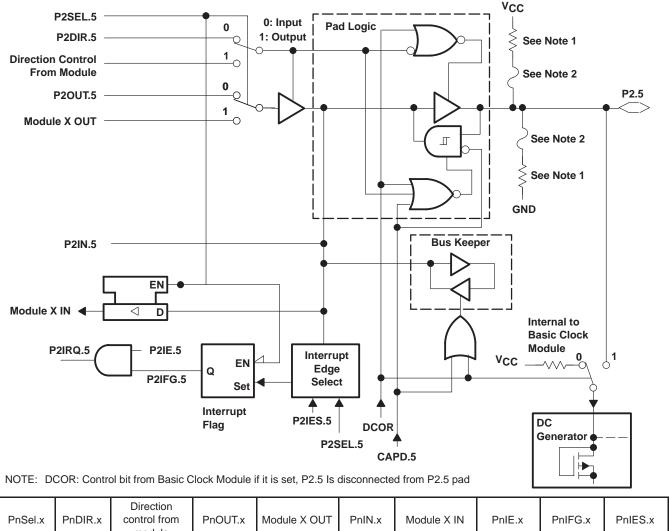
<sup>†</sup>Signal from Timer\_A

NOTES: 1. Optional selection of pullup or pulldown resistors with ROM (masked) versions

2. Fuses for optional pullup and pulldown resistors can only be programmed at the factory (ROM versions only).



Port P2, P2.5, input/output with Schmitt-trigger and R<sub>OSC</sub> function for the Basic Clock module

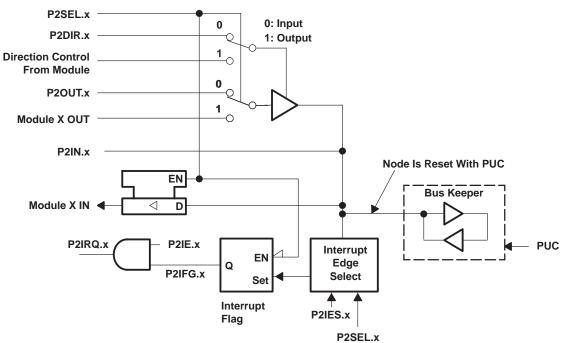


PnSel.x	PnDIR.x	control from module	PnOUT.x	Module X OUT	PnIN.x	Module X IN	PnIE.x	PnIFG.x	PnIES.x
P2Sel.5	P2DIR.5	P2DIR.5	P2OUT.5	V <sub>SS</sub>	P2IN.5	unused	P2IE.5	P2IFG.5	P2IES.5

NOTES: 1. Optional selection of pullup or pulldown resistors with ROM (masked) versions

2. Fuses for optional pullup and pulldown resistors can only be programmed at the factory (ROM versions only).

## Port P2, unbonded bits P2.6 and P2.7



NOTE: x = Bit/identifier, 6 to 7 for port P2 without external pins

P2Sel.x	P2DIR.x	Direction control from module	P2OUT.x	Module X OUT	P2IN.x	Module X IN	P2IE.x	P2IFG.x	P2IES.x
P2Sel.6	P2DIR.6	P2DIR.6	P2OUT.6	V <sub>SS</sub>	P2IN.6	unused	P2IE.6	P2IFG.6	P2IES.6
P2Sel.7	P2DIR.7	P2DIR.7	P2OUT.7	V <sub>SS</sub>	P2IN.7	unused	P2IE.7	P2IFG.7	P2IES.7

NOTE 1: Unbonded bits 6 and 7 of port P2 can be used as software interrupt flags. The interrupt flags can only be influenced by software. They work then as a software interrupt.

## JTAG fuse check mode

MSP430 devices that have the fuse on the TEST terminal have a fuse check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse check current,  $I_{TF}$ , of 1 mA at 3 V, 2.5 mA at 5 V can flow from the TEST pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse check mode and increasing overall system power consumption.

When the TEST pin is taken back low after a test or programming session, the fuse check mode and sense currents are terminated.

Activation of the fuse check mode occurs with the first negative edge on the TMS pin after power up or if TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR the fuse check mode has the potential to be activated.

The fuse check current will only flow when the fuse check mode is active and the TMS pin is in a low state (see Figure 13). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition).

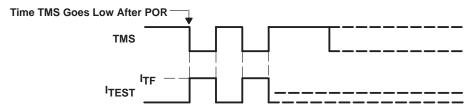


Figure 13. Fuse Check Mode Current, MSP430F11x1A and MSP430C11x1 NOTE:

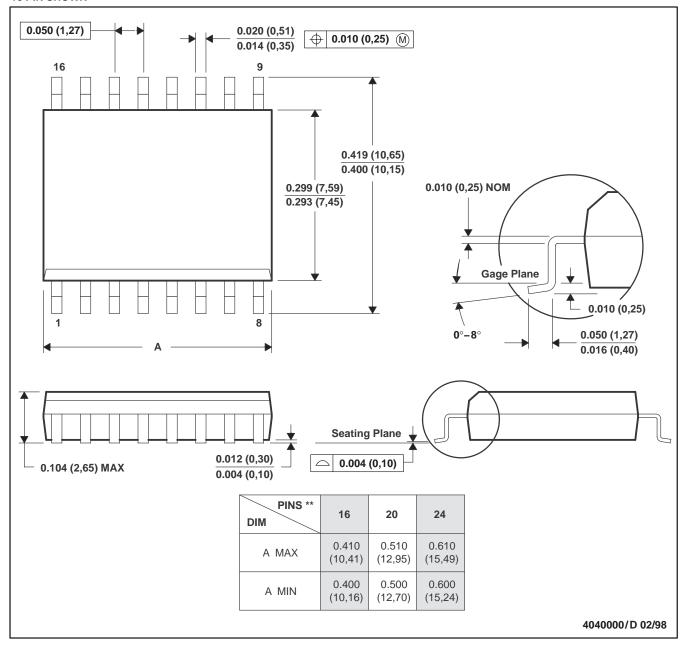
The CODE and RAM data protection is ensured if the JTAG fuse is blown and the 256-bit bootloader access key is used. Also, see the *bootstrap loader* section for more information.

# **MECHANICAL DATA**

# DW (R-PDSO-G\*\*)

#### **16 PIN SHOWN**

# PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
  - D. Falls within JEDEC MS-013

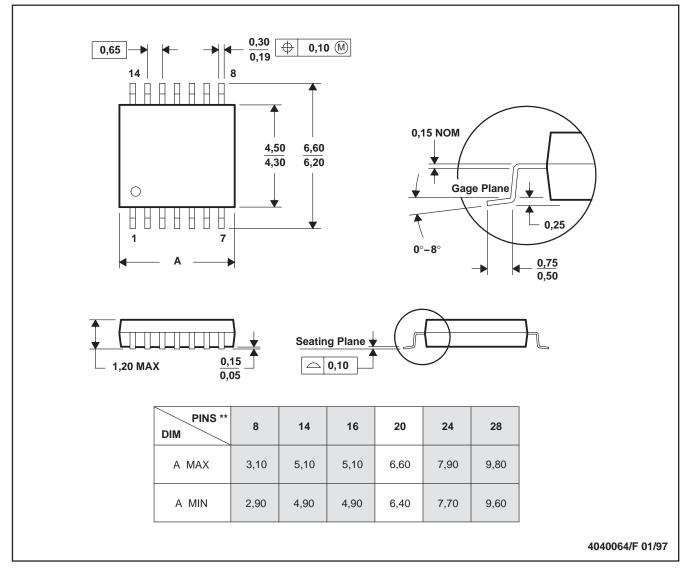


# **MECHANICAL DATA**

# PW (R-PDSO-G\*\*)

#### 14 PINS SHOWN

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

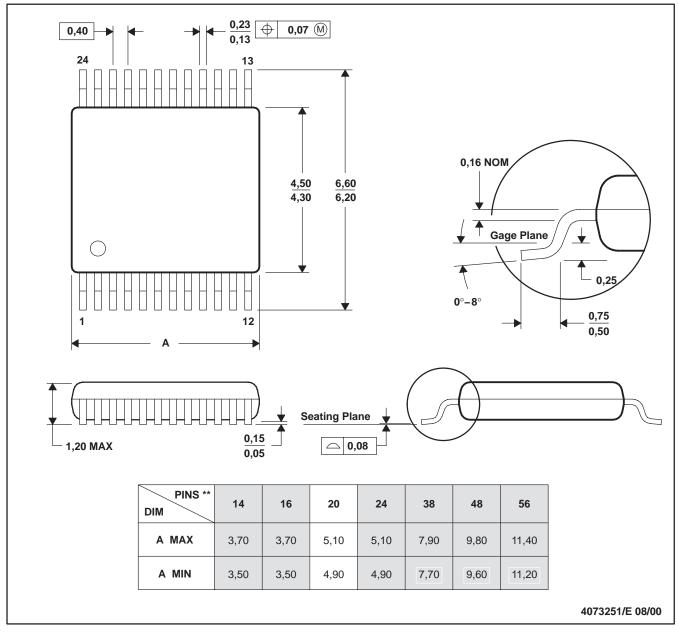
D. Falls within JEDEC MO-153

# **MECHANICAL DATA**

# DGV (R-PDSO-G\*\*)

#### **24 PINS SHOWN**

# **PLASTIC SMALL-OUTLINE**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

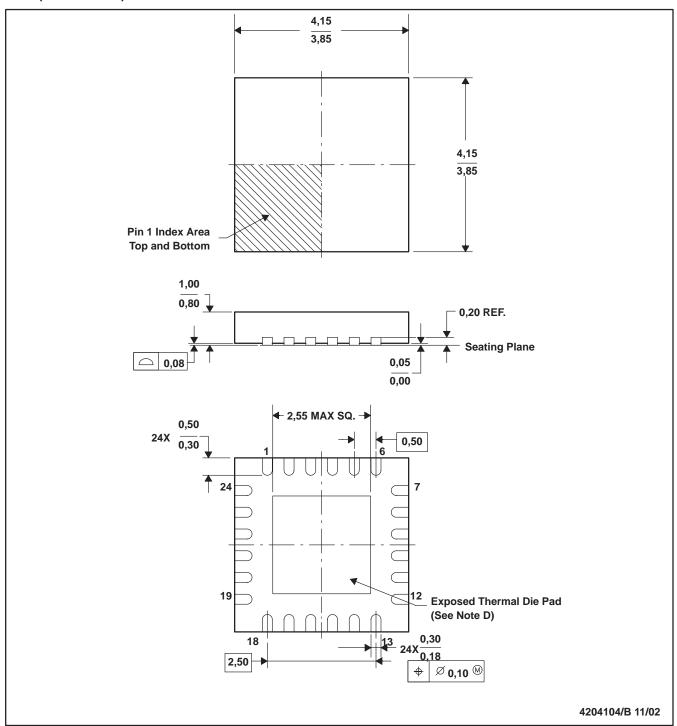
D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194



# **MECHANICAL DATA**

# RGE (S-PQFP-N24)

# PLASTIC QUAD FLATPACK



- NOTES: A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Quad Flatpack, No-leads, (QFN) package configuration.
  - D. The package thermal performance may be enhanced by bonding the thermal die pad to an external thermal plane.
  - E. Falls within JEDEC M0-220.



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